nEXO Double Beta Decay Brian Mong





5/27/16

HQL2016 - Brian Mong

Neutrinos



Neutrino oscillation experiments have demonstrated neutrinos have mass

- Matter/antimatter asymmetry and neutrino masses still a problem for SM
- Majorana neutrinos seem *likely* way to • solve "neutrino problem" in SM



0vββ most sensitive probe for Majorana nature of neutrinos

NSAC long range plan: US-led ton scale $0\nu\beta\beta$ experiment a priority



The current neutrino mass picture

Neutrinoless double beta decay





- Majorana nature of neutrino
- Lepton number violation
- The half-life of $0\nu\beta\beta$ can be used to determine neutrino mass:





Neutrinoless double beta decay



EXO-200 & nEXO projected sensitivities





nEXO – 5 ton detector



Building on EXO-200 successes

- EXO-200 started taking data in May 2011
 - "Observation of Two-Neutrino Double-Beta Decay in 136Xe ...", PRL (2011)
 - "Search for Neutrinoless Double-Beta Decay in 136Xe with EXO-200", PRL (2012)
 - "An improved measurement of the $2\nu\beta\beta$ half-life of Xe-136 with EXO-200", PRC (2013)
 - "Search for Majorana neutrinos with the first two years of EXO-200...", Nature (2014)
- EXO-200 demonstrated the power of the combination of *ionization density*, energy resolution, event multiplicity, and event location
- EXO-200 validated the choice of material and the model that was used to predict the detector background

| Events in ±2σ around Q | Radioactive bkgd prediction during construction | Radioactive bkgd prediction using present Monte Carlo | ¹³⁷ Xe bkgd | Background from Ov analysis fit |
|---------------------------|-------------------------------------------------|-------------------------------------------------------|------------------------|---------------------------------------------|
| 90%CL Upper | 48 | 22 | 7 | 31.1 ± 1.8 ± 3.3 (39 events observed) |
| 90%CL Lower | 9.4 | 3.3 | | |

Optimization from EXO-200 to the nEXO scale

| What | Why | |
|-------------------------------|------------------------------------------------------------------------------------------------------|--|
| ~30x volume/mass | To give sensitivity to the inverted hierarchy | |
| No cathode in the middle | Larger low background volume/no ²¹⁴ Bi in the middle | |
| 6x HV for the same field | Larger detector and one drift cell | |
| >3x electron lifetime | Larger detector and one drift cell | |
| Better photodetector coverage | Energy resolution | |
| SiPM instead of APDs | Higher gain, lower bias, lighter, E resolution | |
| In LXe electronics | Lower noise, more stable, fewer cables/feedthroughs, E resolution, lower threshold for Compton ID | |
| Lower outgassing components | Longer electron lifetime | |
| Different calibration methods | Very "deep" detector (by design) | |
| Deeper site | Less cosmogenic activation | |
| Larger vessels | 5 ton detector and more shielding | |



Energy Resolution: scintillation and charge collection R&D



Energy Resolution: SiPM Photodetectors

Hamamatsu produces devices with QE= ~12% @ 175nm but until now they have refused to sell them un-encapsulated (hence are too radioactive)

First nEXO-specific run at FBK (Italy) provided ~10% QE New "RGB" devices reach 15% QE with 7.7x7.7mm².

[I.Ostrovskiy et al. IEEE TNS 62 (2015) 1.] DOI:10.1109/TNS.2015.2453932



Energy resolution: cold electronics



Charge cluster

(keV)

2.5%

0.6%

0.2%

threshold

600 keV

150 keV

40 keV

Event multiplicity and background discrimination



HQL2016 - Brian Mong

Event location: background identification and suppression

Example: nEXO, 5 yr data, $0\nu\beta\beta @ T_{1/2}=6.6x10^{27}$ yr, projected backgrounds from subsets of the total volume



Event location: background index



While nEXO background index by itself is very good... the fit optimally uses the background vs standoff distance

EXO copper

R&D on (and later qualification of) low background materials is in full swing for nEXO.

A note on the copper that is the dominant background from the TPC vessel:

| | ~U, Th (ppt) |
|--------------------------------------------|--------------|
| EXO-200 ICPMS measurement (Aurubis copper) | < 6, <14 |
| EXO-200 measurement (Aurubis process) | < 4 |
| nEXO measurement of Aurubis copper | < 1 |
| PNNL measurement of electroformed Cu | ~ 0.01 |

Study in progress of the Aurubis process seems to indicate that 0.1 ppt may very well be already achieved.

Barium tagging

136
Xe \rightarrow (136 Ba⁺⁺+ 2e⁻

Barium Tagging: identify barium daughter at $0\nu\beta\beta$ decay site for complete background elimination



nEXO Ba tagging R&D

- Trigger on ionization/scintillation
- In real time estimate if 0v candidate
- Insert probe and electrostatically attract Ba-ion (plate or freeze it)
- Several tagging methods being explored (two of which are):



Ba Tagging: Identifying atoms in solid xenon



Summary

- nEXO is a 5-ton LXe 0vββ experiment that will cover the inverted mass hierarchy
- nEXO is a very flexible and cost effective detector with a clear upgrade path to address possible future science scenarios making the best use of the enriched isotope
- The multi-parameter approach tested in EXO-200 will be even more powerful in the larger nEXO detector ionization density X energy resolution X multiplicity X event location
- A large number of R&D projects are currently underway to verify scale up is feasible



University of Alabama, Tuscaloosa AL, USA – T Didberidze, M Hughes, A Piepke, R Tsang **University of Bern, Switzerland – J-L Vuilleumier** Brookhaven National Laboratory, Upton NY, USA – M Chiu, G De Geronimo, S Li, V Radeka, T Rao, G Smith, T Tsang, B Yu California Institute of Technology, Pasadena CA, USA – P Vogel Carleton University, Ottawa ON, Canada – Y Baribeau, M Bowcock, M Dunford, M Facina, R Gornea, K Graham, P Gravelle, R Killick, T Koffas, C Licciardi, K McFarlane, R Schnarr, D Sinclair Colorado State University, Fort Collins CO, USA – C Chambers, A Craycraft, W Fairbank Jr, T Walton Drexel University, Philadelphia PA, USA – E Callaghan, MJ Dolinski, YH Lin, E Smith, Y-R Yen **Duke University, Durham NC, USA – PS Barbeau, G Swift** University of Erlangen-Nuremberg, Erlangen, Germany – G Anton, R Bayerlein, J Hoessl, P Hufschmidt, A Jamil, T Michel, T Ziegler **IBS Center for Underground Physics, Daejeon, South Korea – DS Leonard** IHEP Beijing, People's Republic of China – G Cao, W Cen, X Jiang, H Li, Z Ning, X Sun, T Tolba, W Wei, L Wen, W Wu, J Zhao ITEP Moscow, Russia – V Belov, A Burenkov, A Karelin, A Kobyakin, A Kuchenkov, V Stekhanov, O Zeldovich University of Illinois, Urbana-Champaign IL, USA – D Beck, M Coon, S Li, L Yang Indiana University, Bloomington IN, USA – JB Albert, S Daugherty, TN Johnson, LJ Kaufman, G Visser, J Zettlemoyer University of California, Irvine, Irvine CA, USA - M Moe Laurentian University, Sudbury ON, Canada – B Cleveland, A Der Mesrobian-Kabakian, J Farine, U Wichoski Lawrence Livermore National Laboratory, Livermore CA, USA – O Alford, J Brodsky, M Heffner, G Holtmeier, A House, M Johnson, S Sangiorgio University of Massachusetts, Amherst MA, USA – S Feyzbakhsh, S Johnston, M Negus, A Pocar McGill University, Montreal OC, Canada – T Brunner, K Murray Oak Ridge National Laboratory, Oak Ridge TN, USA – L Fabris, D Hornback, RJ Newby, K Ziock Pacific Northwest National Laboratory, Richland, WA, USA - EW Hoppe, JL Orrell **Rensselaer Polytechnic Institute, Troy NY, USA – E Brown, K Odgers** SLAC National Accelerator Laboratory, Menlo Park CA, USA – J Dalmasson, T Daniels, S Delaguis, G Haller, R Herbst, M Kwiatkowski, A Odian, M Oriunno, B Mong, PC Rowson, K Skarpaas **University of South Dakota, Vermillion SD, USA – J Daughhetee, R MacLellan** Stanford University, Stanford CA, USA – R DeVoe, D Fudenberg, G Gratta, M Jewell, S Kravitz, D Moore, I Ostrovskiy, A Schubert, M Weber Stony Brook University, SUNY, Stony Brook, NY, USA – K Kumar, O Njoya, M Tarka **Technical University of Munich, Garching, Germany – P Fierlinger, M Marino**

TRIUMF, Vancouver BC, Canada – J Dilling, P Gumplinger, R Krücken, F Retière, V Strickland

Sensitivities for worst and best case nuclear matrix elements Best case (GCM) Worst case (NSM) NF 10²⁹ 10²⁹ NH 10 10²⁸ 10²⁸ m_{ββ} (meV) GCM $m_{\beta\beta}$ (meV) NSM ¹³⁶Xe T_{1/2} ¹³⁶Xe T_{1/2} IH 10²⁷ 10² IH 10² 10²⁶ 10²⁶ 3o Discovery, 50% Probability, 1/10 Cu Bkg 3o Discovery, 50% Probability, 1/10 Cu Bkg EXO200, Ultimate EXO200, Ultimate 10² Sensitivity (90% CL), 1/10 Cu Bkg Sensitivity (90% CL), 1/10 Cu Bkg 10 2 4 6 8 2 4 8 10 Exposure (yrs) Exposure (yrs) NH 10²⁹ 10²⁹ NH 10 10²⁸ 10²⁸ m_{ββ} (meV) GCM m_{ββ} (meV) NSM ¹³⁶Xe T_{1/2} ¹³⁶Xe T_{1/2} 0 IH 10²⁷ 10²⁷ IH 10^{2} 10²⁶ 10²⁶ 3o Discovery, 50% Probability, 1/10 Cu Bkg 3o Discovery, 50% Probability, 1/10 Cu Bkg EXO200, Ultimate EXO200, Ultimate 10^{2} Sensitivity (90% CL), 1/10 Cu Bkg Sensitivity (90% CL), 1/10 Cu Bkg HQL2016 - Brian Mong 1023 **0**5/27/16 2 8 4 2 4 8 Exposure (yrs) Exposure (yrs)



Alpha energy and event locations



HQL2016 - DITATI IVIOUS

$\begin{array}{l} & 214 \text{ Bi ion fraction } (\beta \text{ decay}) \\ \text{Measure ratio of alpha events in LXe} \quad & \frac{A_{P_{o}}^{214}}{A_{P_{o}}^{222}} \\ \text{(Assume 50.3(3.0)\% of }^{214}\text{Pb are ions)} \quad & \frac{A_{P_{o}}^{214}}{A_{P_{o}}^{222}} \\ \text{Neutrals Decay in flight} \\ & \frac{A_{P_{o}}^{214}}{A_{P_{o}}^{218}} = (1 - f'_{\alpha} + f'_{\alpha}\epsilon_{P_{o}})(1 - f_{\beta} + f_{\beta}\epsilon_{B_{i}}) \quad f_{\beta} \text{ is daughter ion fraction of } \beta \text{ decay} \\ \end{array}$

Measure 2 alpha decays in LXe fid. vol. Deduce beta decay ion fraction



 $f_{\rm B}$: 76.4 ± 5.7 %

| Good news for |
|-----------------|
| barium tagging! |

J. B. Albert et al. (EXO-200 Collaboration) Phys. Rev. C 92, 045504

Using ²²²Rn-²¹⁸Po events to determine ion drift parameters



MC Model Parameters:

 $v_1 = 1.48 \pm 0.01 \text{ mm/s}$ $v_2 = 0.83 \pm 0.01 \text{ mm/s}$ $C = 12600 \pm 660$ $N = 6^{+4.9} + 10^5$ $D = 0.61 \pm 0.04 \text{ mm}^2/\text{s}$

<u>Mobility of ²¹⁸Po</u> $\mu_1 = 0.390 \pm 0.006 \text{ cm}^2/(\text{keV} \cdot \text{s})$ $\mu_2 = 0.219 \pm 0.004 \text{ cm}^2/(\text{keV} \cdot \text{s})$ other ions are 0.13-0.28 cm²/(keV \cdot \text{s})

C is ratio of reaction lifetime to electron lifetime:

(t_e ~3 ms, t_{reaction}~ 40s) N is ratio or neutralization time to electron lifetime (N=50 * C):

An important result for Ba tagging: (t_e ~3 ms, t_{neut}>1000s)